

RELIABILITY MONITOR

| PRODUCT | MONITOR DATE | DATE CODE | ASSEMBLY FACILITY | ASSEMBLY LOT NO | PROCESS TYPE | PACKAGE TYPE |
|---------|--------------|-----------|-------------------|-----------------|--------------|--------------|
| DS2108 | Nov-97 | 9735 B1 | ANAM, K. | DN721124AAD | 5.0μ NI | 24 SOIC |

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
 Bake, 125°C, 24 Hr
 Moisture Soak, 30°C/60% RH, 144 Hr
 Vapor Phase Reflow, 3 Passes, P-20875

| | | |
|-------------|-------------------|--------------|
| <u>0 Hr</u> | <u>Electrical</u> | <u>Cum %</u> |
| 249/0 | 238/0 | 0.0% |

Sonoscan
P-20992

Post Vapor Phase

| | | | | |
|---|-----------------------|-----------------------|-------------|----------------------|
| Infant / High Voltage Life 125°C, 6.0 V. P-20993, P-21077 | <u>48 Hr</u> 233/0 | <u>336 Hr</u> 77/0 | <u>1KHr</u> | <u>*Failure Rate</u> |
|---|-----------------------|-----------------------|-------------|----------------------|

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

| | | | |
|--|----------------------|-------------|--------------|
| Temp Cycle -55°C to +125°C P-21078 | <u>300 ~</u> 40/0 | <u>1K ~</u> | <u>Cum %</u> |
|--|----------------------|-------------|--------------|

| | | | |
|---|-----------------------|---------------|----------------------|
| Biased Moisture 85°C/85% RH, 5.5 V. P-21079 | <u>274 Hr</u> 77/0 | <u>959 Hr</u> | <u>Cum %</u> 0.0% |
|---|-----------------------|---------------|----------------------|

| | | | |
|--|--|----------------------|----------------------|
| Autoclave 121°C/100% RH, 2 Atmos P-21080 | | <u>96 Hr</u> 37/0 | <u>Cum %</u> 0.0% |
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Failure Mode

Failure Analysis